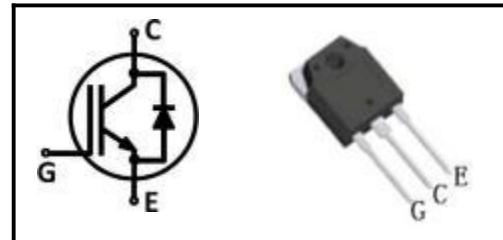


特征/Features

- 饱和压降为正温度系数，易于并联使用
Easy parallel switching capability due to positive temperature coefficient in V_{CEsat}
- 内置快速恢复二极管
Built-in fast recovery diode
- 高可靠性及热稳定性，良好的参数一致性
High reliability and thermal stability, good parameter consistency

应用领域/Applications

- 太阳能逆变器/Solar Inverter
- 焊接机/Welding Machine
- 不间断电源/UPS
- 功率因数校正/PFC
- PTC加热器/PTC heater
- 气候压缩机Climate compressor



型号/Type	打标/Marking	封装/Package
QMT40N120E	QM40N120E	TO-3P

最大额定值/Maximum Rated Values

Item	Symbol	Value	Unit
集电极-发射极电压 Collector-emitter voltage	V_{CE}	1200	V
集电极电流 DC collector current, limited by T_{vjmax} $T_C=25^\circ\text{C}$ $T_C=130^\circ\text{C}$	I_C	80 40	A
集电极脉冲电流 Pulsed collector current, t_p limited by T_{jmax1}	I_{Cpuls}	160	
二极管正向电流 Diode forward current, limited by T_{jmax} $T_C=25^\circ\text{C}$ $T_C=100^\circ\text{C}$	I_F	80 40	
二极管脉冲电流 Diode pulsed current, t_p limited by T_{jmax1})	I_{Fpuls}	160	
栅极-发射极电压 Gate-emitter voltage	V_{GE}	± 20	V
瞬态栅极-发射极电压 Transient Gate-emitter voltage ($t_p \leq 10\mu\text{s}, D < 0.01$)		± 30	
耗散功率 Power dissipation $T_C=25^\circ\text{C}$ $T_C=100^\circ\text{C}$	P_{tot}	428 214	W
工作结温 Operating junction temperature	T_j	-40~175	
储存温度 Storage temperature	T_{stg}	-55~150	°C
焊接温度 Soldering temperature, wave soldering 1.6mm (0.063in.) from case for 10s		260	
安装扭矩, M3 螺钉最大安装过程: 3 Mounting torque, M3 screw Maximum of mounting processes: 3	M	0.6	Nm

1) Defined by design. Not subject to production test.

电学特性/Electrical Characteristics

静态特性/Static Characteristics (at $T_j=25^\circ\text{C}$ unless otherwise specified)

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
集电极-发射极击穿电压 Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V, I_C=0.25mA$	1200	-	-	V
集电极-发射极饱和电压 Collector-emitter saturation voltage	$V_{CE(\text{sat})}$	$V_{GE}=15V, I_C=40A$ $T_j=25^\circ\text{C}$	-	1.6	2.1	
		$T_j=150^\circ\text{C}$	-	1.9	-	
		$T_j=175^\circ\text{C}$	-	2.0	-	
阈值电压 G-E threshold voltage	$V_{GE(\text{th})}$	$I_C=1.5mA, V_{CE}=V_{GE}$	5.0	5.8	6.5	
集电极-发射极漏电流 C-E leakage current	I_{CES}	$V_{CE}=1200V, V_{GE}=0V$ $T_j=25^\circ\text{C}$	-	-	0.1	mA
		$T_j=175^\circ\text{C}$	-	-	4.0	
栅极-发射极漏电流 G-E leakage current	I_{GES}	$V_{CE}=0V, V_{GE}=20V$	-	-	250	nA

动态特性/Dynamic Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
输入电容 Input capacitance	C_{iss}	$V_{CE}=25V, V_{GE}=0V, f=1MHz$	-	8150	-	pF
输出电容 Output capacitance	C_{oss}		-	96	-	
反馈电容 Reverse transfer capacitance	C_{rss}		-	118	-	
栅电荷 Gate charge	Q_G	$V_{CC}=400V, I_C=40A, V_{GE}=15V$	-	465	-	nC

热学特性/Thermal Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
结-外壳热阻 IGBT thermal resistance, junction-case	R_{thJC}	$R_{thJC} = 0.28 \text{ K/W}$	-	0.28	0.35	K/W
二极管结-外壳热阻 Diode thermal resistance, junction-case	R_{thJCD}		-	-	0.80	
结-环境热阻 Thermal Resistance, junction- ambient	R_{thJA}		-	-	40	

IGBT开关特性(感性负载) / IGBT Switching Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
开通延迟时间 Turn-on delay time	$t_{d(on)}$	$T_J=25^\circ C, V_{CC}=600V, I_C=40A, V_{GE}=0/15V, R_G=10\Omega, Inductive load$	-	113	-	ns
上升时间 Rise time	t_r		-	76	-	
关断延迟时间 Turn-off delay time	$t_{d(off)}$		-	738	-	
下降时间 Fall time	t_f		-	80	-	
开通损耗 Turn-on energy	E_{on}		-	2.56	-	
关断损耗 Turn-off energy	E_{off}		-	2.13	-	
开关损耗 Total switching energy	E_{ts}		-	4.69	-	
开通延迟时间 Turn-on delay time	$t_{d(on)}$		-	118	-	
上升时间 Rise time	t_r	$T_J=175^\circ C, V_{CC}=600V, I_C=40A, V_{GE}=0/15V, R_G=10\Omega, Inductive load$	-	54	-	ns
关断延迟时间 Turn-off delay time	$t_{d(off)}$		-	738	-	
下降时间 Fall time	t_f		-	162	-	
开通损耗 Turn-on energy	E_{on}		-	3.62	-	
关断损耗 Turn-off energy	E_{off}		-	3.54	-	
开关损耗 Total switching energy	E_{ts}		-	7.16	-	

二极管开关特性/Diode Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
二极管正向压降 Diode forward voltage	V_F	$V_{GE}=0V, I_F=40A$	-	2.35	3.0	V
		$T_J=25^\circ C$	-	2.1	-	
		$T_J=150^\circ C$	-	2.0	-	
反向恢复时间 Diode reverse recovery time	t_{rr}	$T_J=25^\circ C, V_R=400V, I_F=40A, diF/dt=550A/\mu s$	-	165	-	ns
反向恢复电荷 Diode reverse recovery charge	Q_{rr}		-	1.49	-	μC
反向恢复峰值电流 Diode peak reverse recovery current	I_{rrm}		-	20.0	-	A
反向恢复时间 Diode reverse recovery time	t_{rr}	$T_J=25^\circ C, V_R=400V, I_F=40A, diF/dt=550A/\mu s$	-	285	-	ns
反向恢复电荷 Diode reverse recovery charge	Q_{rr}		-	3.51	-	μC
反向恢复峰值电流 Diode peak reverse recovery current	I_{rrm}		-	28.8	-	A

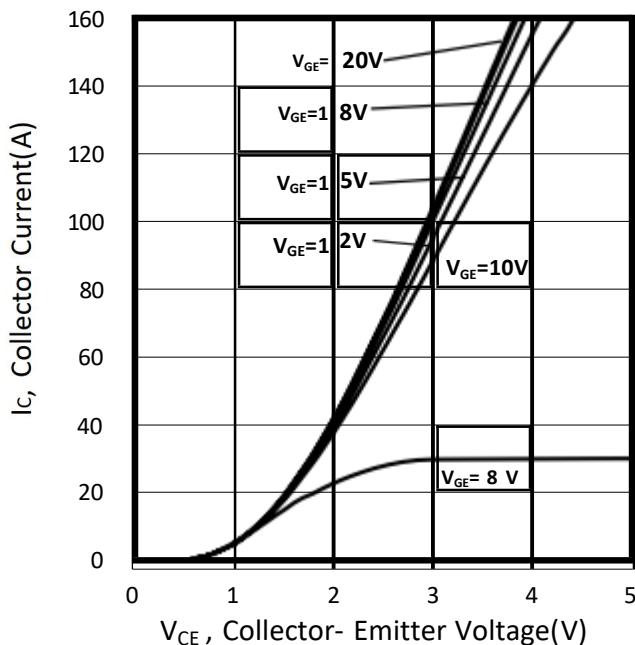


Figure 1. 典型输出特性/Typical output characteristic($T_{vj}=25^\circ\text{C}$)

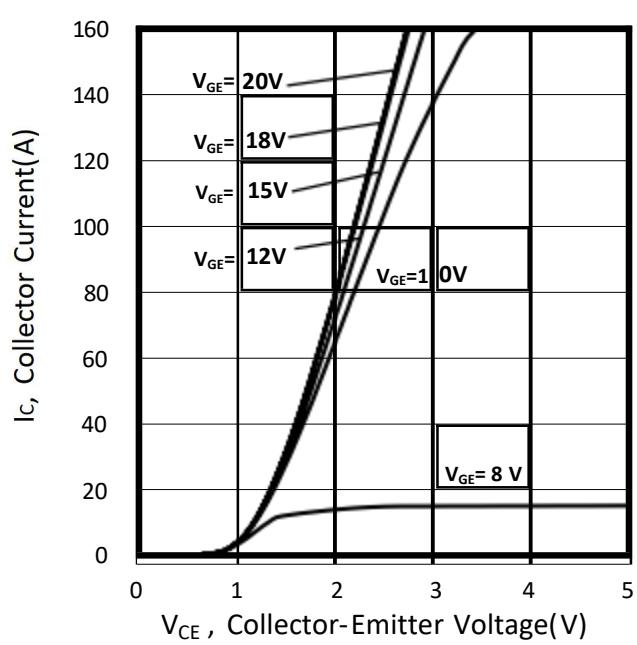


Figure 2. 典型输出特性/Typical output characteristic ($T_{vj} = 175^\circ\text{C}$)

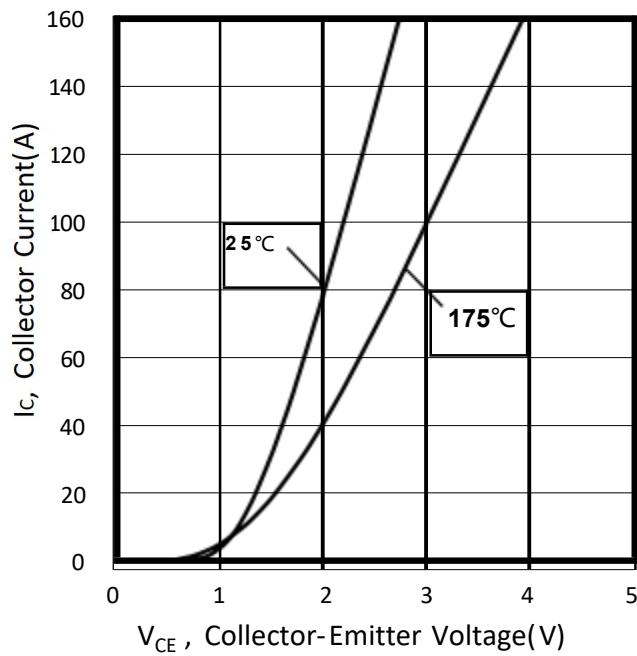


Figure 3. 典型 $V_{CE(\text{sat})}$ - T_j 特性曲线/Typical $V_{CE(\text{sat})}$ - T_j characteristic ($V_{GE}=15\text{V}$)

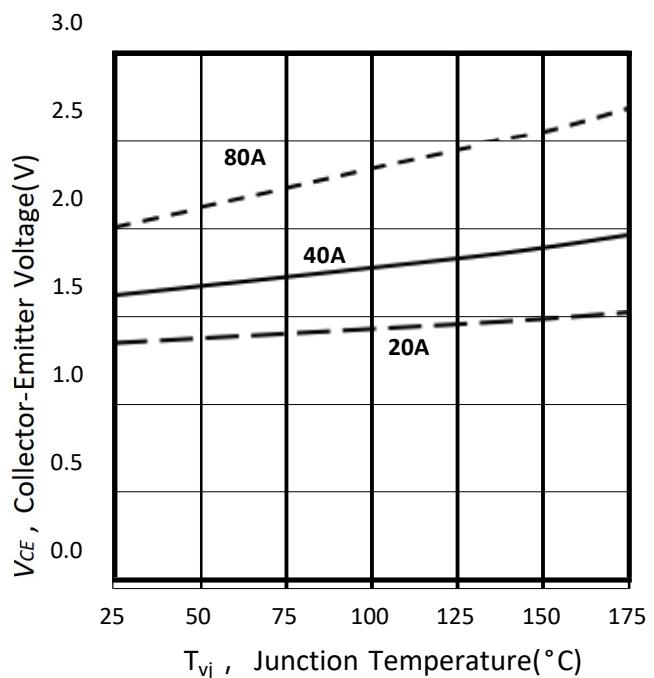


Figure 4. 典型 $V_{CE(\text{sat})}$ - T_j 特性曲线/Typical $V_{CE(\text{sat})}$ - T_j characteristic ($V_{GE}=15\text{V}$)

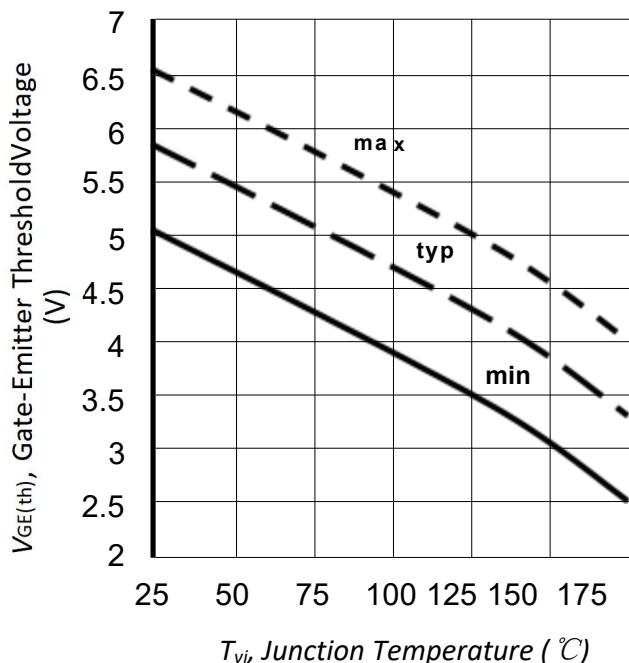


Figure 5. 典型 $V_{GE(th)}$ - T_j 特性曲线/Typical $V_{GE(th)}$ - T_j characteristic ($I_c=1.5\text{mA}$)

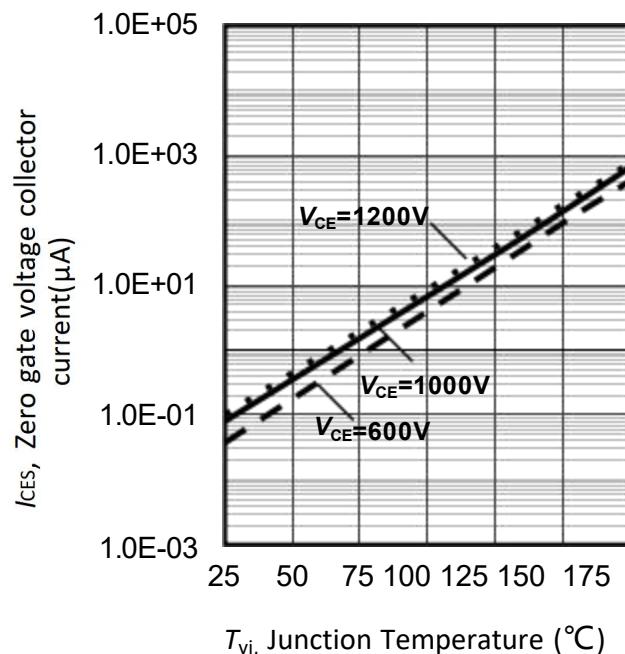


Figure 6. 典型 I_{CES} - T_j 特性曲线/Typical I_{CES} - T_j characteristic ($V_{GE}=0\text{V}$)

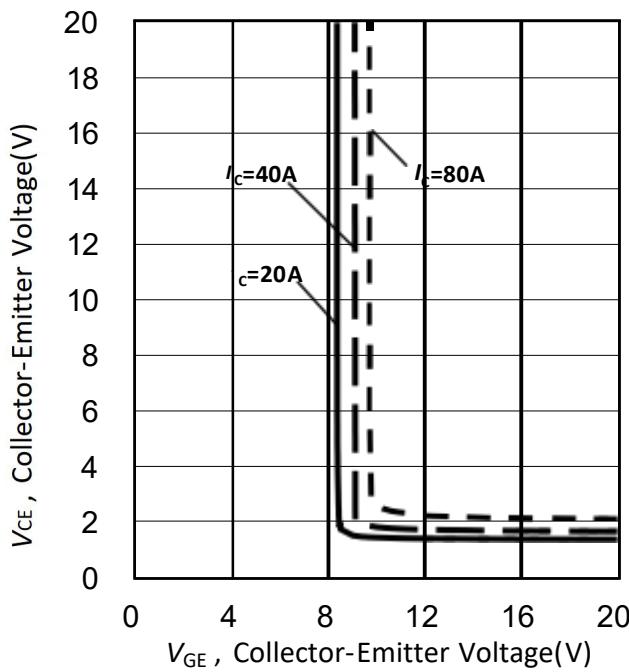


Figure 7. 典型 $V_{CE(sat)}$ - $V_{GE(th)}$ 特性曲线/Typical $V_{CE(sat)}$ - $V_{GE(th)}$ characteristic ($T_{vj}=25^\circ\text{C}$)

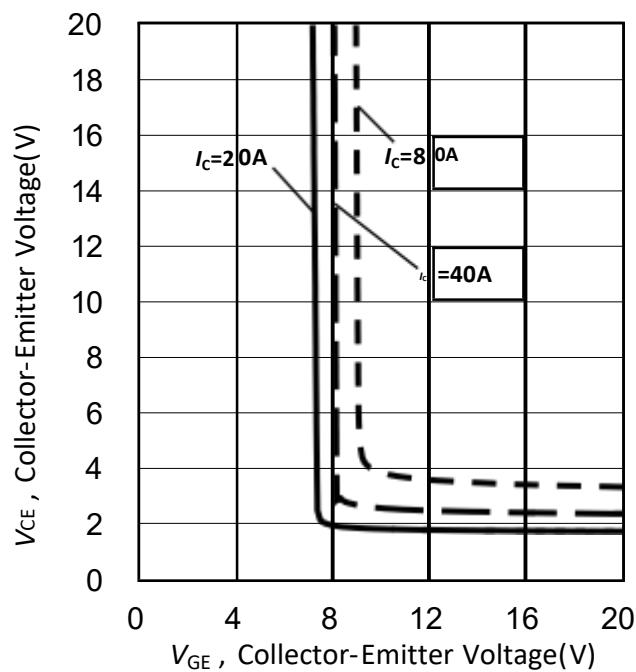


Figure 8. 典型 $V_{CE(sat)}$ - $V_{GE(th)}$ 特性曲线/Typical $V_{CE(sat)}$ - $V_{GE(th)}$ characteristic ($T_{vj}=175^\circ\text{C}$)

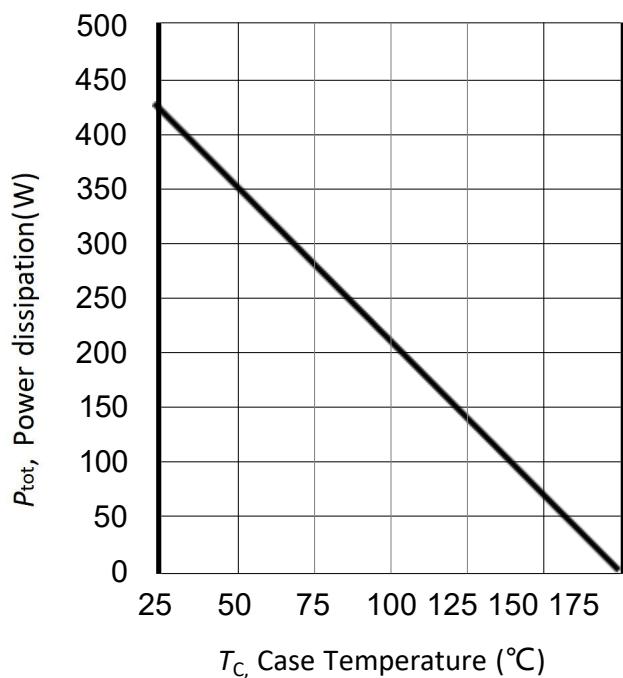


Figure 9. 功耗与外壳温度的关系/Power dissipation as a function of case temperature
 $(T_{vj} \leqslant 175^{\circ}\text{C})$

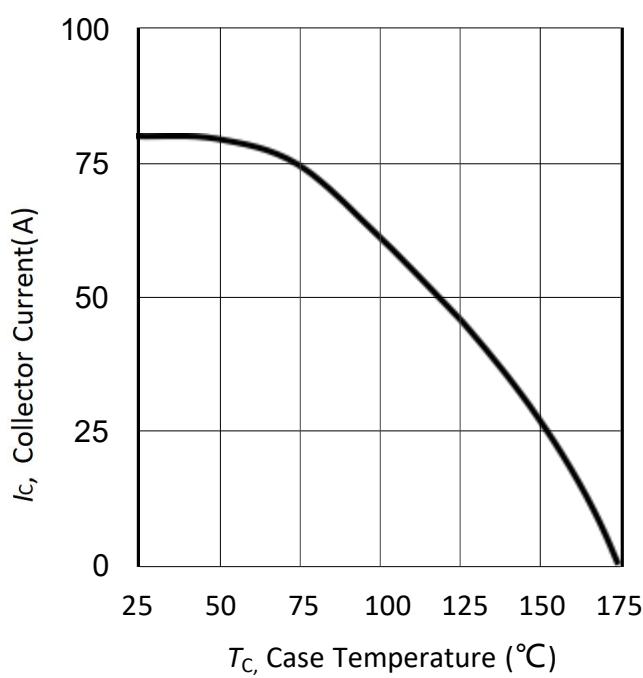


Figure 10. 集电极电流与外壳温度的关系/Collector current as a function of case temperature
 $(T_{vj} \leqslant 175^{\circ}\text{C}, V_{GE} \geq 15\text{V})$

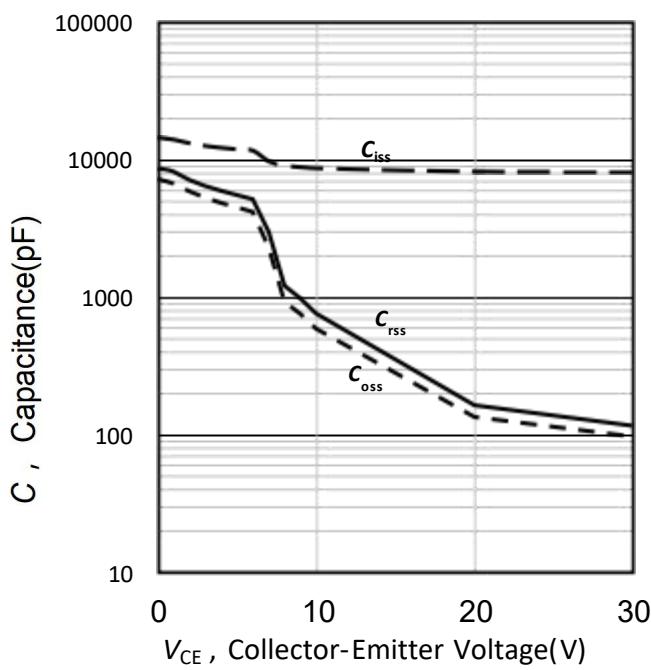


Figure 11. 典型电容与集电极-发射极电压的关系
/Typical capacitance as a function of collector-emitter voltage($V_{GE}=0\text{V}$, $f=1\text{MHz}$)

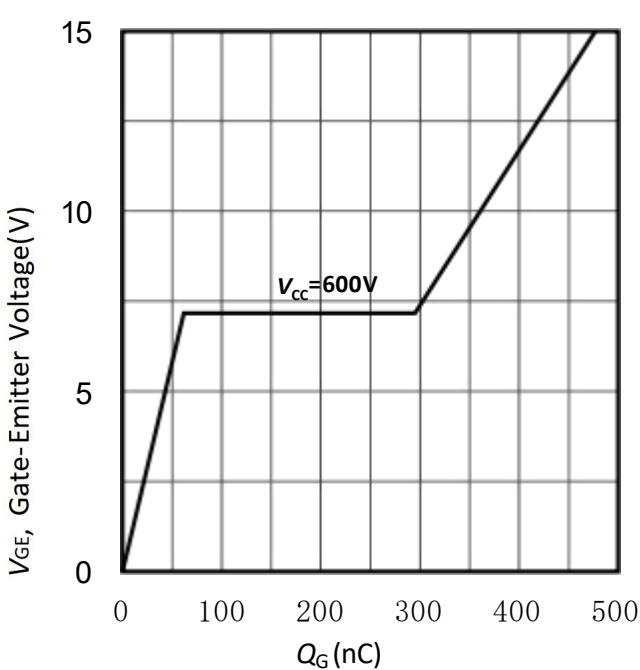


Figure 12. 典型栅极电荷/Typical gate charge

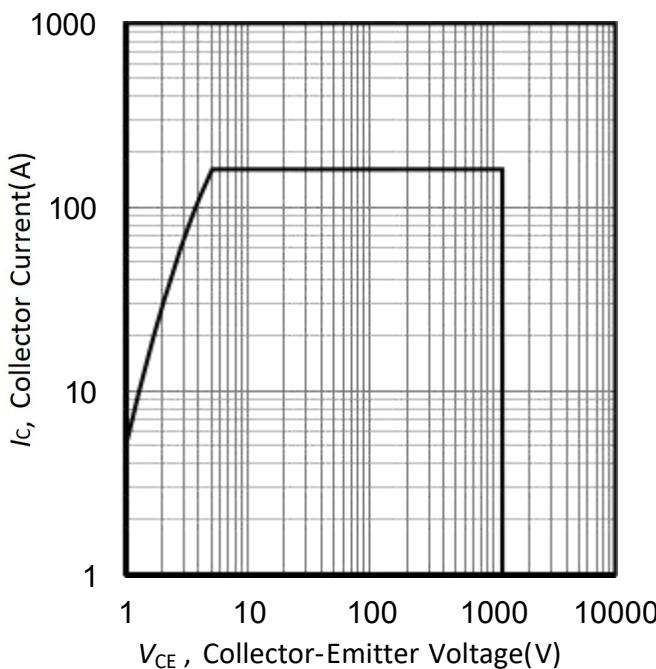


Figure 13. IGBT反向偏置安全工作区/IGBT reverse bias safe operating area
 $(T_{vj} \leq 175^{\circ}\text{C}, V_{GE}=15\text{V})$

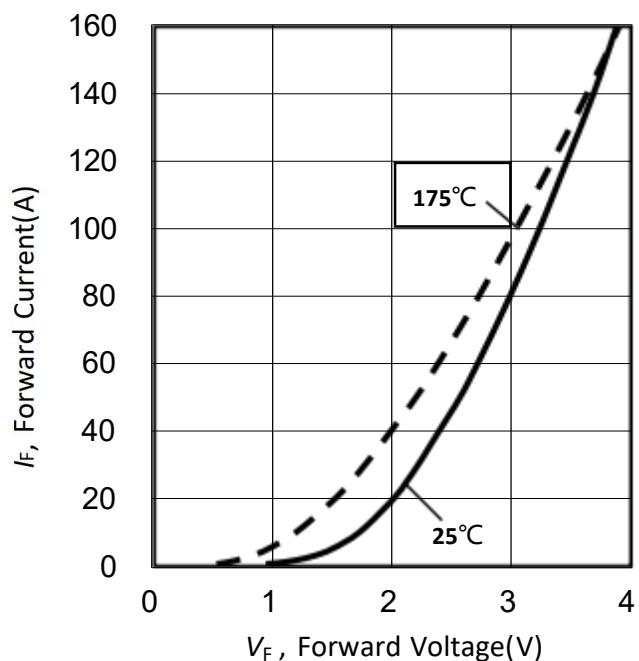


Figure 14. 典型二极管正向电流与正向电压的函数关系/Typical diode forward current as a function of forward voltage

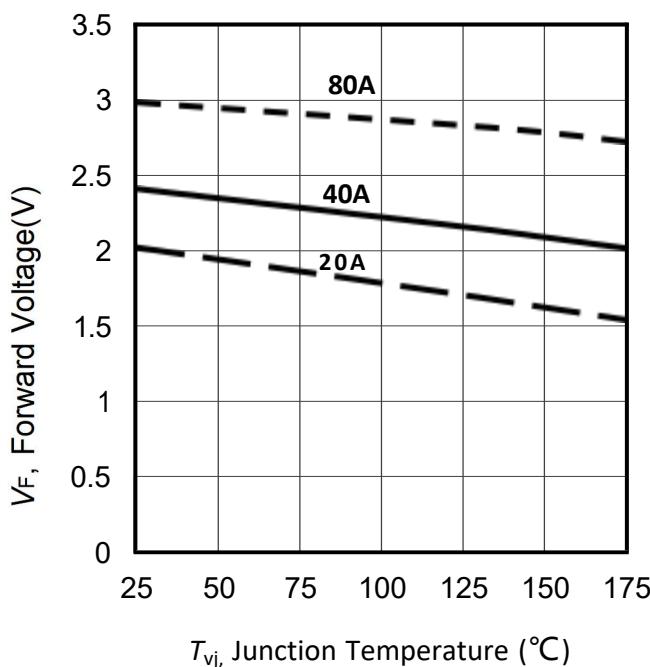


Figure 15. 典型二极管正向电压为结温函数/Typical diode forward voltage as a function of junction temperature

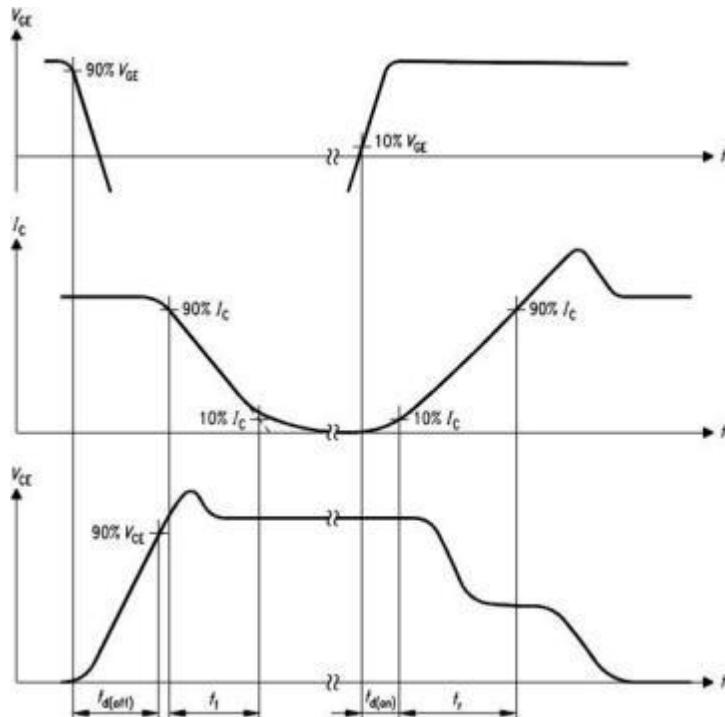


Figure A. 开关时间的定义/Definition of switching times

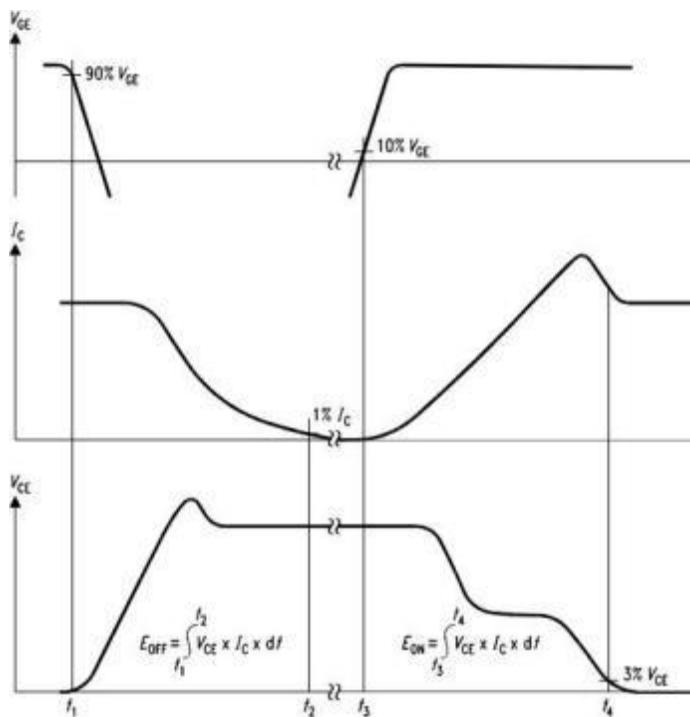


Figure B. 开关损耗的定义/
Definition of switching losses

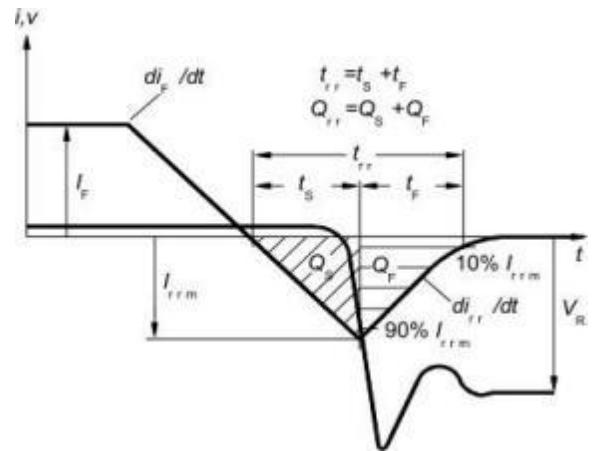


Figure C. 二极管开关特性的定
义/Definition of diodes
switching characteristics

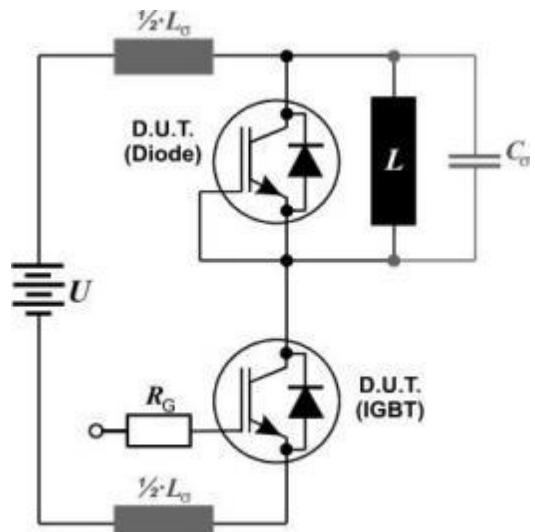
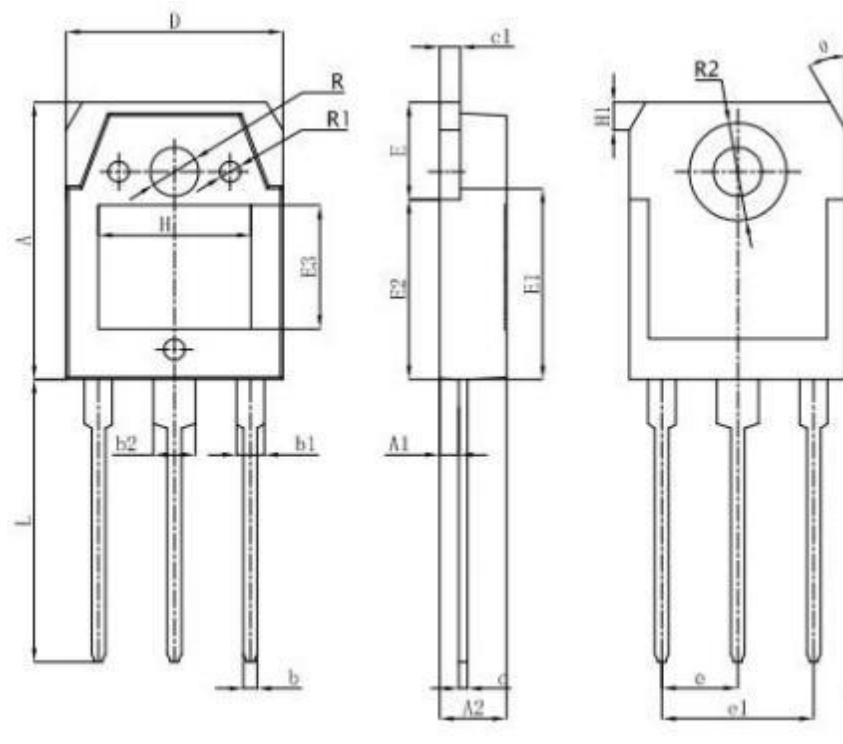


Figure D. 开关测试电路/Switching
test circuit

TO-3P



SYMBOL	mm		
	MIN	NOM	MAX
A	4.80	5.00	5.20
A1	2.21	2.41	2.61
A2	1.85	2.00	2.15
b	1.11	1.21	1.36
b ₂	1.91	2.01	2.21
b ₄	2.91	3.01	3.21
c	0.51	0.61	0.75
D	20.70	21.00	21.30
D1	16.25	16.55	16.85
E	15.50	15.80	16.10
E1	13.00	13.30	13.60
E2	4.80	5.00	5.20
E3	2.30	2.50	2.70
e	5.44BSC		
L	19.62	19.92	20.22
L1	-	-	4.30
ΦP	3.40	3.60	3.80
ΦP1	-	-	7.30
S	6.15BSC		

修订历史/Revision History:

修订 /Revision	主题 (自上次修订以来的主要变化) /Subjects (major changes since last revision)	日期 /Date
1.0	Initial Version	2022-06
2.0	Update the English and Chinese versions	2023-04

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